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SERIAL NUMBER	FILING DATE	FIRST NAMED APPLICANT	A	TTORNEY DOCKET NO.	
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Γ	•	ר ְ	EXAMINER		
			ART UNIT	PAPER NUMBER	
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	•	ים.	ATE MAILED:		
	EXAM	INER INTERVIEW SUMMARY RECORI	•		
All participants (applican	t, applicant's representative, PT	O personnel):			
(1)	Green	(3)			
11. 1	1	(3)	· · · · · · · · · · · · · · · · · · ·		
(2) Vern /	1000 QQ1	(4)			
Date of interview	6/1/94				
Type: Telephonic	☐ Personal (copy is given to	☐ applicant ☐ applicant's representative).			
/ Exhibit shown or demons	tration conducted:	☐ No. If yes, brief description:			
	<u> </u>				
Agreement 🔲 was reach	ed with respect to some or all o	of the claims in question.			
Claims discussed:			***		
dentification of prior art	discussed:				
escription of the general	nature of what was agreed to if	an agreement was reached, or any other comme	nts:		
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and we	ould be a	ting on it sher	76		
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A fuller description, if n	ecessary and a conv of the am	nondmente if omileble which shows			
ttached. Also, where no c	opy of the amendments which	nendments, if available, which the examiner agr would render the claims allowable is available, a	eed would render ti summary thereof m	he claims allowable must bo ust be attached.)	
Intess the paragraphs belo	ow have been checked to indic	ate to the contrary, A FORMAL WRITTEN RE	SPONSE TO THE	LAST OFFICE ACTION I	
		CE OF THE INTERVIEW (e.g., items 1 – 7 on the given one month from this interview date to prove			
		ite record of the substance of the interview.			
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		ncluding any attachments) reflects a complete rece action, and since the claims are now allowable	sponse to each of all	ne objections, rejections and	
response requiremen	nts of the last Office action.		y Join plated for	The considered to fulfill the	
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PTOL-413 (REV. 1-84)		Examiner's Si	nature		